



3/20/2012

PRODUCT RELIABILITY REPORT  
FOR

**DS2411, Rev A2**

**Maxim Integrated Products**

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**Conclusion:**

The following qualification successfully meets the quality and reliability standards required of all Maxim products:

DS2411, Rev A2

In addition, Maxim's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at <http://www.maxim-ic.com/TechSupport/dsreliability.html>.

**Device Description:**

A description of this device can be found in the product data sheet. You can find the product data sheet at [http://dbserv.maxim-ic.com/l\\_datasheet3.cfm](http://dbserv.maxim-ic.com/l_datasheet3.cfm).

**Reliability Derating:**

The Arrhenius model will be used to determine the acceleration factor for failure mechanisms that are temperature accelerated.

$AfT = \exp((Ea/k)(1/T_u - 1/T_s)) = tu/ts$   
AfT = Acceleration factor due to Temperature  
tu = Time at use temperature (e.g. 55°C)  
ts = Time at stress temperature (e.g. 125°C)  
k = Boltzmann's Constant ( $8.617 \times 10^{-5}$  eV/K)  
Tu = Temperature at Use (°K)  
Ts = Temperature at Stress (°K)  
Ea = Activation Energy (e.g. 0.7 ev)

The activation energy of the failure mechanism is derived from either internal studies or industry accepted standards, or activation energy of 0.7ev will be used whenever actual failure mechanisms or their activation energies are unknown. All deratings will be done from the stress ambient temperature to the use ambient temperature.

An exponential model will be used to determine the acceleration factor for failure mechanisms, which are voltage accelerated.

$AfV = \exp(B(V_s - V_u))$   
AfV = Acceleration factor due to Voltage  
Vs = Stress Voltage (e.g. 7.0 volts)  
Vu = Maximum Operating Voltage (e.g. 5.5 volts)  
B = Constant related to failure mechanism type (e.g. 1.0, 2.4, 2.7, etc.)

The Constant, B, related to the failure mechanism is derived from either internal studies or industry accepted standards, or a B of 1.0 will be used whenever actual failure mechanisms or their B are unknown. All deratings will be done from the stress voltage to the maximum operating voltage. Failure rate data from the operating life test is reported using a Chi-Squared statistical model at the 60% or 90% confidence level (Cf).

The failure rate, Fr, is related to the acceleration during life test by:

$Fr = X/(ts * AfV * AfT * N * 2)$   
X = Chi-Sq statistical upper limit  
N = Life test sample size

Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

$$\text{MTTF} = 1/\text{Fr}$$

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this device/process is:

<b>FAILURE RATE:</b>	<b>MTTF (YRS):</b>	<b>126324</b>	<b>FITS:</b>	<b>0.9</b>
	<b>DEVICE HOURS:</b>	<b>2237882793</b>	<b>FAILS:</b>	<b>1</b>

Only data from Operating Life or similar stresses are used for this calculation.

The parameters used to calculate this failure rate are as follows:

<b>Cf:</b> 60%	<b>Ea:</b> 0.7	<b>B:</b> 0	<b>Tu:</b> 25 °C	<b>Vu:</b> 5.5 Volts
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The reliability data follows. At the start of this data is the device information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available and may contain some generic data. **Bold** Product Number denotes specific product data.

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#### Device Information:

Process:	SA E6P, 2P-1M, HP Vt, N+ ESD, -300 Poly TempCo, PF-Ring, 8 inch Wafer
Passivation:	TEOS Oxide-Nitride Passivation
Die Size:	45 x 29
Number of Transistors:	1750
Interconnect:	Aluminum / 0.5% Copper
Gate Oxide Thickness:	150 Å

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#### ELECTRICAL CHARACTERIZATION

DESCRIPTION	DATE CODE/PRODUCT/LOT	CONDITION	READPOINT	QTY	FAILS	FA#
ESD SENSITIVITY	0248 <b>DS2411</b>	ZK316811AD EOS/ESD S5.1 HBM 1000 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0248 <b>DS2411</b>	ZK316811AD EOS/ESD S5.1 HBM 2000 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0248 <b>DS2411</b>	ZK316811AD EOS/ESD S5.1 HBM 4000 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0248 <b>DS2411</b>	ZK316811AD EOS/ESD S5.1 HBM 8000 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0248 <b>DS2411</b>	ZK316811AD IEC 61000-4-2 CONTACT 2000 VOLTS	10 PUL'S	3	0	
ESD SENSITIVITY	0248 <b>DS2411</b>	ZK316811AD IEC 61000-4-2 CONTACT 4000 VOLTS	10 PUL'S	3	0	
ESD SENSITIVITY	0248 <b>DS2411</b>	ZK316811AD IEC 61000-4-2 CONTACT 8000 VOLTS	10 PUL'S	3	0	
LATCH-UP	0248 <b>DS2411</b>	ZK316811AD JESD78, I-TEST 125C		6	0	
LATCH-UP	0248 <b>DS2411</b>	ZK316811AD JESD78, V-SUPPLY TEST 125C		6	0	
			Total:		0	

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**OPERATING LIFE**

DESCRIPTION	DATE CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
HIGH VOLTAGE LIFE	0636 DS32B35	QH639098A 125C, 3.6 VOLTS	168 HRS	100	0	
HIGH VOLTAGE LIFE	0636 DS32B35	QH639098A 125C, 3.6 VOLTS	168 HRS	100	0	
HIGH TEMP OP LIFE	0636 DS32C35	QH639098A 125C, 3.6 VOLTS	1000 HRS	100	0	
HIGH VOLTAGE LIFE	0636 DS32B35	QH639098A 125C, 3.6 VOLTS	168 HRS	100	0	
HIGH VOLTAGE LIFE	0636 DS32C35	QH639098AF 125C, 3.6 VOLTS	168 HRS	100	0	
HIGH VOLTAGE LIFE	0636 DS32C35	QH639098A 125C, 3.6 VOLTS	168 HRS	100	0	
HIGH VOLTAGE LIFE	0636 DS32C35	QH639098A 125C, 3.6 VOLTS	168 HRS	100	0	
HIGH TEMP OP LIFE	0720 DS1851	QK707606BB 125C, 5.5 VOLTS	192 HRS	77	0	
HIGH TEMP OP LIFE	0832 DS2505	WH941772A 125C, 6.0 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0837 DS2505	WH942720A 125C, 6.0 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0838 DS2505	WH941773A 125C, 6.0 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0906 DS5250	WK942982D 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0921 DS7865	WQ946139A 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0923 DS5250	WK947706A 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0923 DS1748	WN945795L 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0925 DS21Q50	WK945230A 125C, 3.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0933 DS3231S	WH946471D 125C, 5.5 VOLTS	408 HRS	77	0	
HIGH TEMP OP LIFE	0940 DS80C320	WK048689A 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0944 DS80C320	WK049844A 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0947 DS1341	WD048116A 125C, 5.5 VOLTS	192 HRS	77	0	
HIGH TEMP OP LIFE	0948 DS1856	WM049367A 125C, 5.5 VOLTS	1000 HRS	77	1	40023508
HIGH TEMP OP LIFE	0949 DS80C320	WK049846A 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1021 DS1804	WD049849A 125C, 5.5 VOLTS	192 HRS	45	0	
HIGH TEMP OP LIFE	1022 MAX34405	QD056611A 125C, 3.6 VOLTS	192 HRS	45	0	
HIGH TEMP OP LIFE	1035 DS18S20	FJ157931AB 125C, 5.5 VOLTS	1000 HRS	80	0	
HIGH TEMP OP LIFE	1037 DS1340	WD157959A 125C, 5.5 VOLTS	192 HRS	77	0	
HIGH TEMP OP LIFE	1050 DS1856	WM158219A 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1050 DS1856	WM158219A 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1052 DS1856	FJ162135DB 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1052 DS1856	FJ162135DB 125C, 5.5 VOLTS	1000 HRS	77	0	

HIGH TEMP OP LIFE	1052	DS1856	FJ162076CC 125C, 5.5 VOLTS	1000	HRS	77	0
HIGH TEMP OP LIFE	1052	DS1856	FJ162076CC 125C, 5.5 VOLTS	1000	HRS	77	0
HIGH TEMP OP LIFE	1103	DS18S20	FD162367AC 125C, 5.5 VOLTS	1000	HRS	80	0
HIGH TEMP OP LIFE	1113	DS18S20	FD166067AB 125C, 5.5 VOLTS	1000	HRS	80	0
HIGH TEMP OP LIFE	1113	DS3911	ZJ167332AB- 125C, 5.5 VOLTS	192	HRS	48	0
HIGH TEMP OP LIFE	1127	DS2501	QE168668AB 125C, 6.0 VOLTS	1164	HRS	77	0
HIGH TEMP OP LIFE	1127	DS2501	QE168668A 125C, 6.0 VOLTS	1164	HRS	77	0
HIGH TEMP OP LIFE	1127	DS2501	QE168668A 125C, 6.0 VOLTS	1164	HRS	77	0
HIGH TEMP OP LIFE	1128	DS18S20	FH167920AB 125C, 5.5 VOLTS	1000	HRS	80	0
HIGH TEMP OP LIFE	1129	DS1347	ZS167344AD 125C, 5.5 VOLTS	192	HRS	77	0
HIGH TEMP OP LIFE	1138	DS18S20	FD271756AB 125C, 5.5 VOLTS	1000	HRS	80	0
<b>Total:</b>							<b>1</b>

**FAILURE RATE:**      **MTTF (YRS):**      **126324**      **FITS:**      **0.9**

**DEVICE HOURS:** **2237882793**      **FAILS:**      **1**